

SDRAM產品預燒時間之研究

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摘要

Recently, the semiconductor industrial markets are expanding rapidly. To survive on the competitive markets, one must enhance the manufacturing technology and improve the quality and reliability. Cost issue must be considered as well. The purpose of this study is to generate an optimal Burn-In strategy that can meet the reliability requirement and minimize the Burn-In cost. The first issue of Burn-In study is "What is the distribution of the product life time". This study performs the goodness of fit test and bases on the test result to confirm the statistical distribution assumption. The other issue is how to determine the Burn-In time. This study considers the "Reliability Objective Model" and "Minimizing Cost Model" under general condition and Burn-In error condition. Finally, sentivity analysis is performed and optimal Burn-In time is determined.

關鍵字：reliability, Burn-In model, SDRAM, Burn-In error